

ILNAS

Institut luxembourgeois de la normalisation
de l'accréditation, de la sécurité et qualité
des produits et services

ILNAS-EN IEC 62506:2023

Methods for product accelerated testing

Verfahren für beschleunigte
Produktprüfungen

Méthodes d'essais accélérés de produits

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**Methods for product accelerated testing
(IEC 62506:2023)**

Méthodes d'essais accélérés de produits
(IEC 62506:2023)

Verfahren für beschleunigte Produktprüfungen
(IEC 62506:2023)

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European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Rue de la Science 23, B-1040 Brussels

European foreword

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The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2024-09-12
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2026-12-12

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In the official version, for Bibliography, the following notes have to be added for the standard indicated:

- IEC 62740:2015 NOTE Approved as EN 62740:2015 (not modified)
IEC 60812 NOTE Approved as EN IEC 60812
IEC 61163-2 NOTE Approved as EN IEC 61163-2
IEC 60300-3-4 NOTE Approved as EN IEC 60300-3-4
IEC 60068 (series) NOTE Approved as EN 60068 (series)
IEC 61014 NOTE Approved as EN 61014
IEC 61163-1 NOTE Approved as EN 61163-1
IEC 61164:2004 NOTE Approved as EN 61164:2004 (not modified)
IEC 61125:2018 NOTE Approved as EN IEC 61125:2018 (not modified)

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 Where an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cencenelec.eu.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050-192	-	International electrotechnical vocabulary - Part 192: Dependability	-	-
IEC 60300-3-5	-	Dependability management - Part 3-5: Application guide - Reliability test conditions and statistical test principles	-	-
IEC 60605-2	-	Equipment reliability testing - Part 2: Design of test cycles	-	-
IEC 60721	series	Classification of environmental conditions	EN 60721	series
IEC 61123	2019	Reliability testing - Compliance test plans for success ratio	EN IEC 61123	2020
IEC 61124	2023	Reliability testing - Compliance tests for constant failure rate and constant failure intensity	EN IEC 61124	2023
IEC 61649	2008	Weibull analysis	EN 61649	2008
IEC 61709	-	Electric components - Reliability - Reference conditions for failure rates and stress models for conversion	EN 61709	-
IEC 61710	-	Power law model - Goodness-of-fit tests and estimation methods	EN 61710	-
IEC 62429	-	Reliability growth - Stress testing for early failures in unique complex systems	EN 62429	-



INTERNATIONAL STANDARD

NORME INTERNATIONALE



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